## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination NAITO ET AL. Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0204069 A1	10-2004	Cui et al.	455/557
*	В	US-2003/0014521 A1	01-2003	Elson et al.	709/225
*	С	US-2006/0274828 A1	12-2006	Siemens et al.	375/240.01
*	D	US-6,535,743 B1	03-2003	Kennedy et al.	455/456.1
*	E	US-6,484,093 B1	11-2002	Ito et al.	701/211
*	F	US-6,314,295 B1	11-2001	Kawamoto, Yoji	455/456.2
*	G	US-6,650,970 B2	11-2003	Odashima et al.	701/1
	Н	US-			
	1	US-			
	j	US-			
	К	US-			
0.00	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2001-148092	05-2001	JP	Ito Yasuo et al	
	0					
	Р					
	Q.					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.